

Features

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology
- ★ 100% EAS Guaranteed

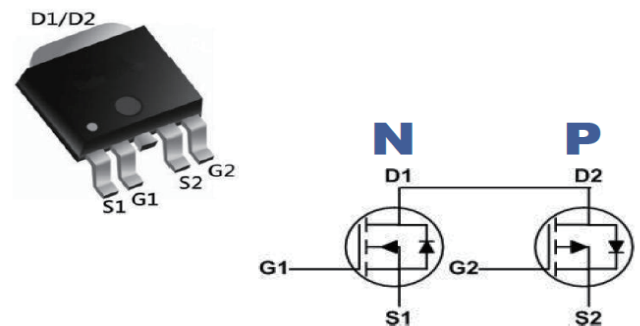
Product Summary

BVDSS	RDSON	ID
30V	15mΩ	20A
-30V	25mΩ	-23A

Description

The 3020 is th high performance complementary N-ch and P-ch MOSFETs with high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The 3020 meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

TO252-4 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-Ch	N-Ch	
V _{DS}	Drain-Source Voltage	30	-30	V
V _{GS}	Gate-Source Voltage	±20	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	20	-23	A
I _b @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	15	-14	A
I _{DM}	Pulsed Drain Current ²	60	-60	A
EAS	Single Pulse Avalanche Energy ³	26.6	38	mJ
P _D @T _C =25°C	Total Power Dissipation ⁴	20.8	20.8	W
P _D @T _A =25°C	Total Power Dissipation ⁴	2	2	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ¹	---	62	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	---	6	°C/W

N-Channel Electrical Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BVDSS Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	---	0.023	---	$V/^\circ\text{C}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance ²	$V_{GS}=10V, I_D=10A$	---	15	20	$m\Omega$
		$V_{GS}=4.5V, I_D=6A$	---	20	25	
$V_{GS(th)}$	Gate Threshold Voltage		1	---	2.5	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient	$V_{GS}=V_{DS}, I_D=250\mu A$	---	-4.2	---	$mV/^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=24V, V_{GS}=0V, T_J=25^\circ\text{C}$	---	---	1	μA
		$V_{DS}=24V, V_{GS}=0V, T_J=55^\circ\text{C}$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=5V, I_D=10A$	---	14	---	S
R_g	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$	---	2.3	---	Ω
Q_g	Total Gate Charge (4.5V)		---	5	---	nC
Q_{gs}	Gate-Source Charge	$V_{DS}=20V, V_{GS}=4.5V, I_D=10A$	---	1.11	---	
Q_{gd}	Gate-Drain Charge		---	2.61	---	
$T_{d(on)}$	Turn-On Delay Time		---	7.7	---	ns
T_r	Rise Time	$V_{DD}=12V, V_{GS}=10V,$ $R_G=3.3\Omega, I_D=6A$	---	46	---	
$T_{d(off)}$	Turn-Off Delay Time		---	11	---	
T_f	Fall Time		---	3.6	---	
C_{iss}	Input Capacitance		---	416	---	pF
C_{oss}	Output Capacitance	$V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$	---	62	---	
C_{rss}	Reverse Transfer Capacitance		---	51	---	

Diode Characteristics

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
I_S	Continuous Source Current ^{1,5}	$V_G=V_D=0V$, Force Current	---	---	20	A
I_{SM}	Pulsed Source Current ^{2,5}		---	---	40	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$	---	---	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.1\text{mH}, I_{AS}=20A$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

P-Channel Electrical Characteristics (T_J=25°C unless otherwise specified)

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250uA	-30	---	---	V
ΔBV _{DSS} /ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C, I _D =-1mA	---	-0.021	---	V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =-10V, I _D =-8A	---	25	30	mΩ
		V _{GS} =-4.5V, I _D =-6A	---	30	35	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1	---	-2.5	V
ΔV _{GS(th)}	V _{GS(th)} Temperature Coefficient		---	-4.2	---	mV/°C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-24V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =-24V, V _{GS} =0V, T _J =55°C	---	---	5	
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±20V, V _{DS} =0V	---	---	±100	nA
g _{fs}	Forward Transconductance	V _{DS} =-5V, I _D =-8A	---	12.6	---	S
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	15	---	Ω
Q _g	Total Gate Charge (-4.5V)		---	9.8	---	nC
Q _{gs}	Gate-Source Charge	V _{DS} =-20V, V _{GS} =-4.5V, I _D =-6A	---	2.2	---	
Q _{gd}	Gate-Drain Charge		---	3.4	---	
T _{d(on)}	Turn-On Delay Time		---	16.4	---	ns
T _r	Rise Time	V _{DD} =-24V, V _{GS} =-10V, R _G =3.3Ω, I _D =-1A	---	20.2	---	
T _{d(off)}	Turn-Off Delay Time		---	55	---	
T _f	Fall Time		---	10	---	
C _{iss}	Input Capacitance		---	930	---	pF
C _{oss}	Output Capacitance	V _{DS} =-15V, V _{GS} =0V, f=1MHz	---	148	---	
C _{rss}	Reverse Transfer Capacitance		---	115	---	

Diode Characteristics

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
I _S	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	-23	A
I _{SM}	Pulsed Source Current ^{2,5}		---	---	-35	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V, I _S =-1A, T _J =25°C	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper. 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD}=-25V,V_{GS}=-10V,L=0.1mH,I_{AS}=-30A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

N-Channel Typical Performance Characteristics

Figure 1: Output Characteristics

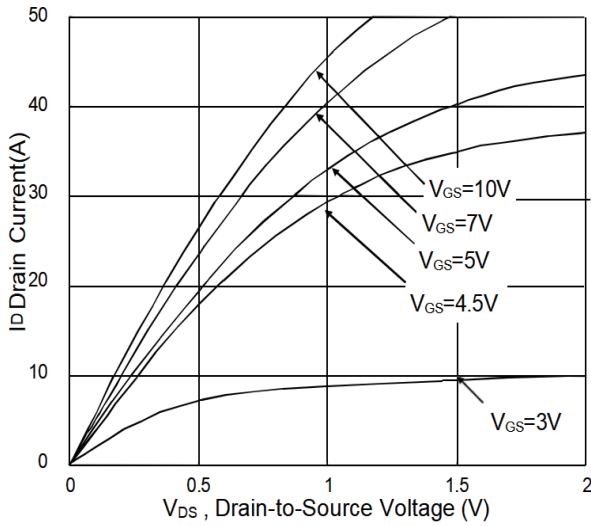


Figure 2: On-Resistance vs. Gate-Source

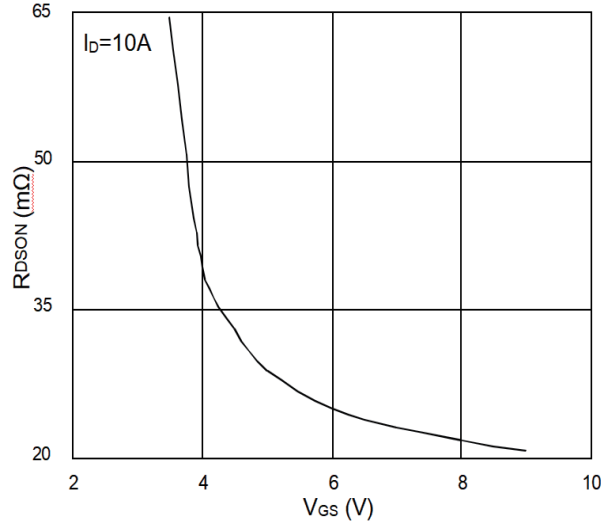


Figure 3: Forward Characteristics Of Reverse

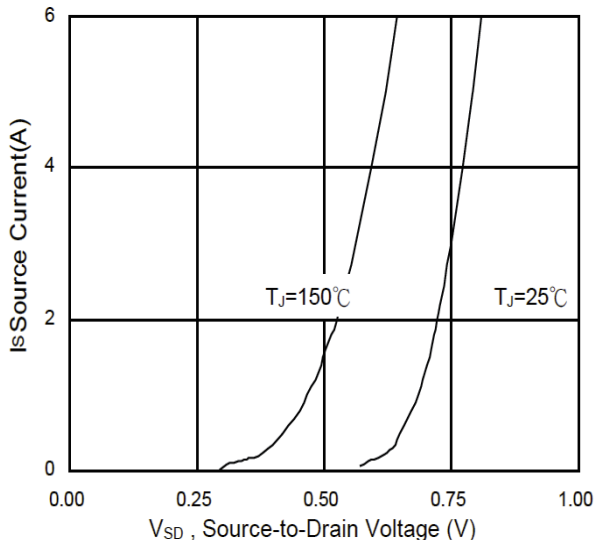


Figure 4: Gate-Charge Characteristics

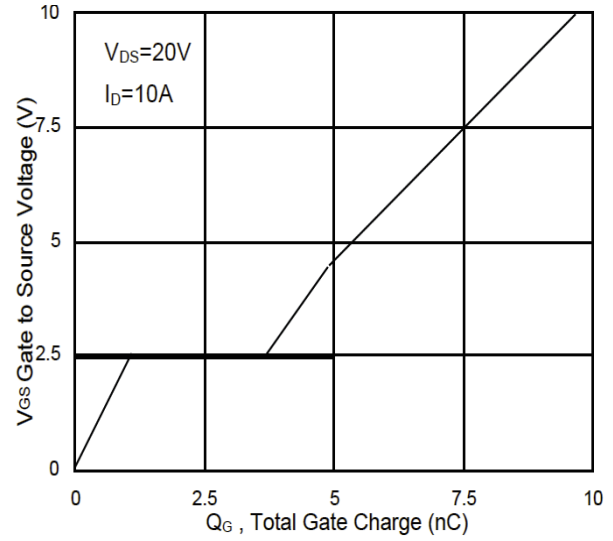


Figure 5: Normalized VGS(th) vs. TJ

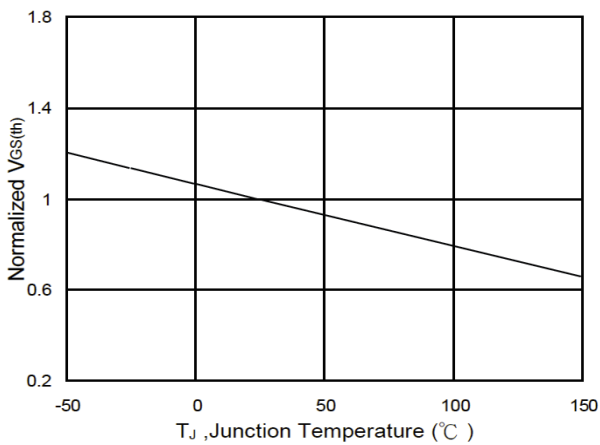
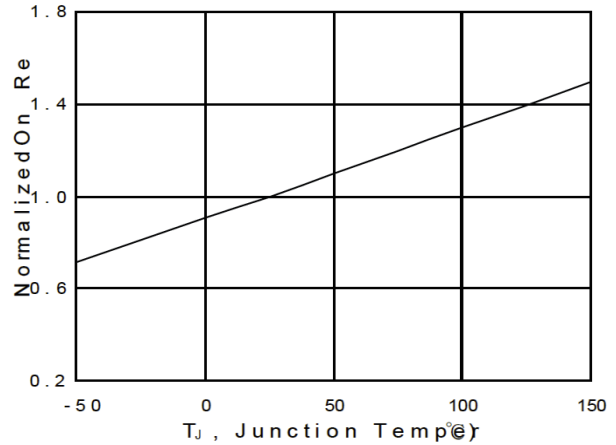


Figure 6: Normalized RDS(on) vs. TJ



N-Channel Typical Performance Characteristics

Figure7:Capacitance

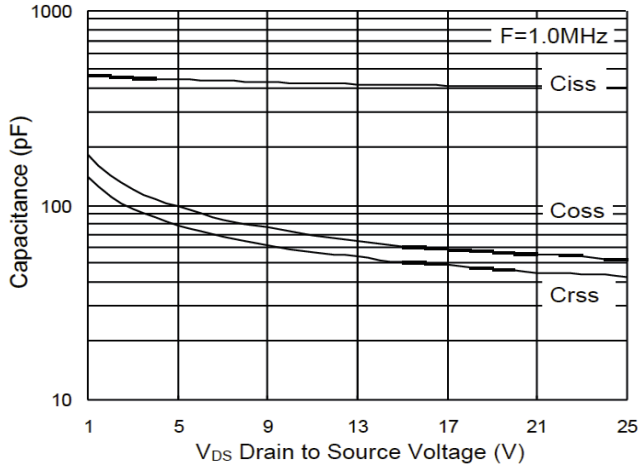


Figure 8 Safe Operating Area

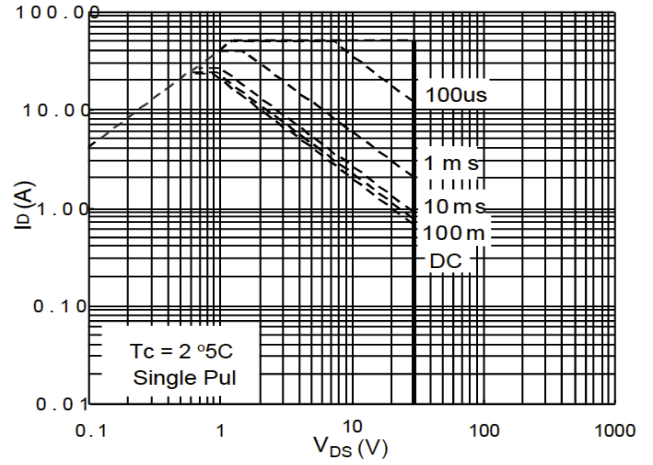


Figure9:Normalized Maximum Transient Thermal Response

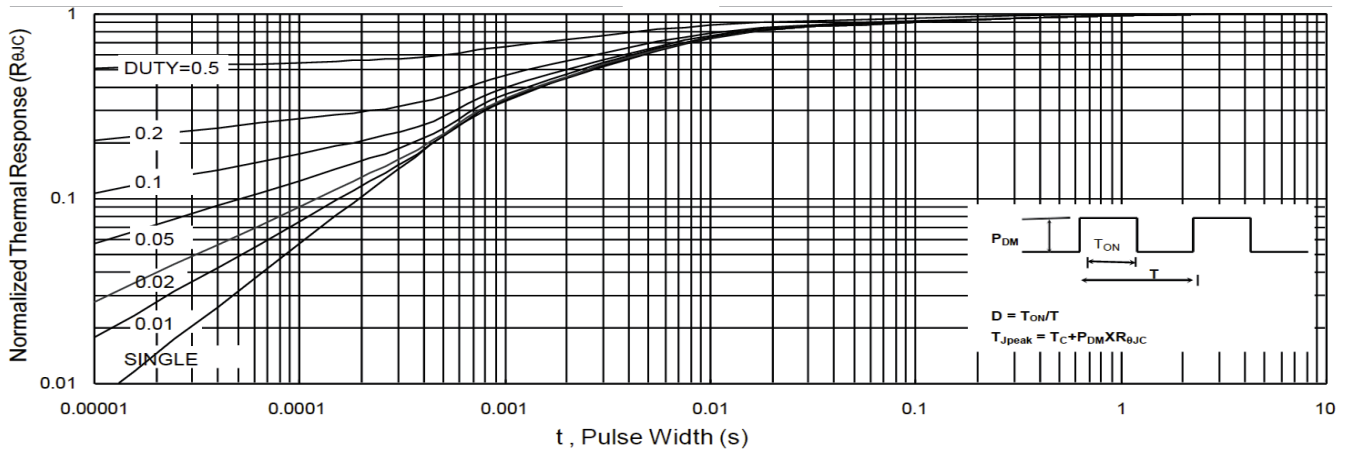


Figure10:Switching Time Waveform

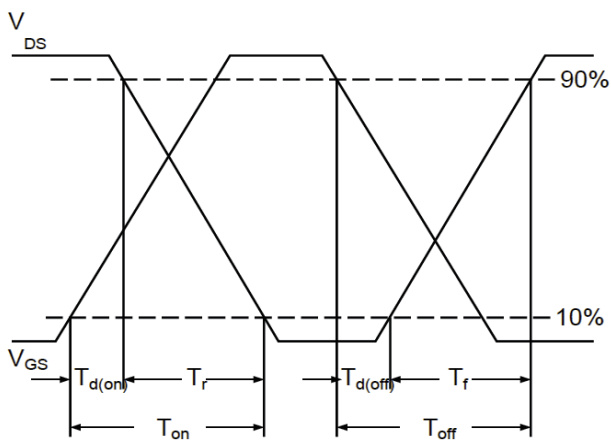
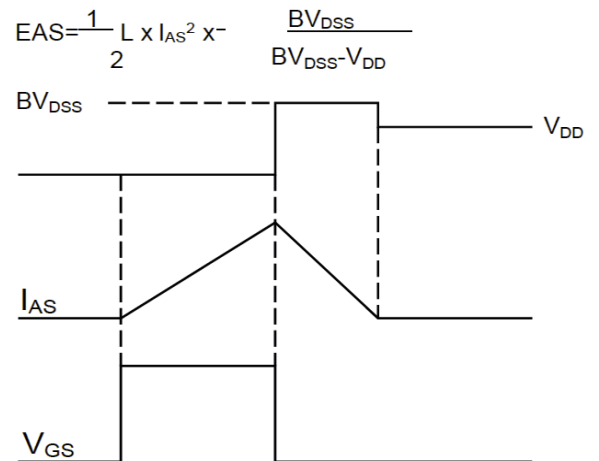


Figure11:Unclamped Inductive Switching



P-Channel Typical Performance Characteristics

Figure1:Capacitance

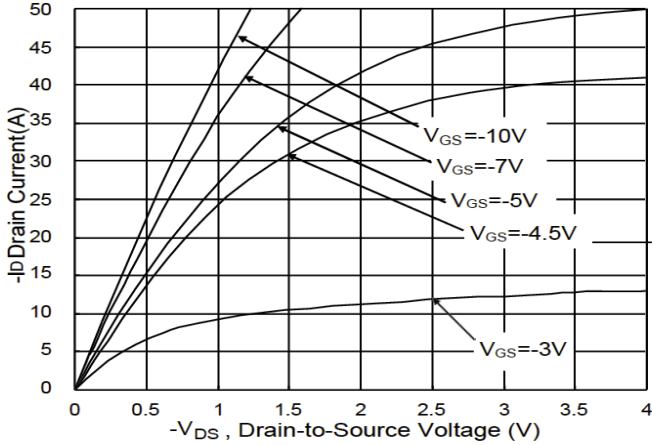


Figure 2:On-Resistance v.s Gate-Source

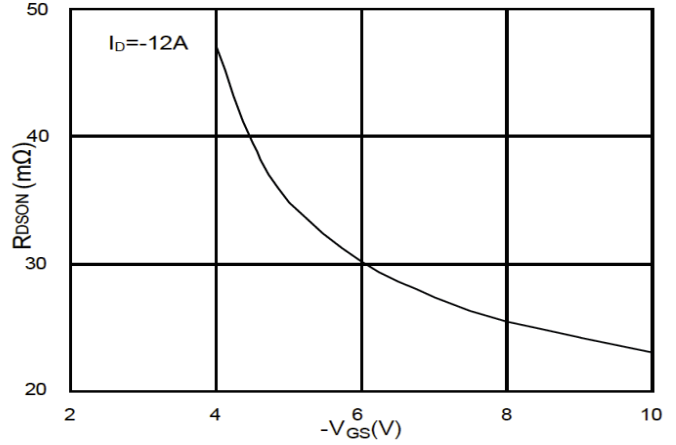


Figure3:Forward Characteristics Of Reverse

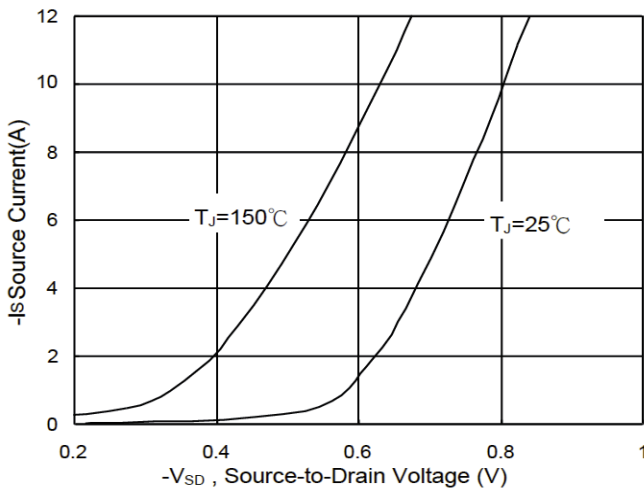


Figure4:Gate-Charge Characteristics

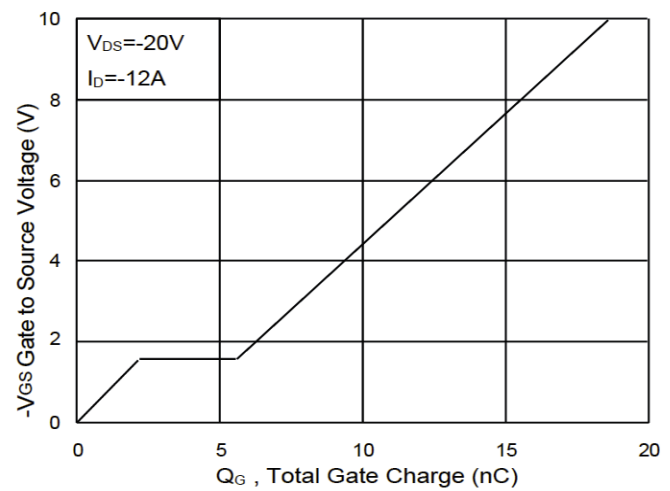


Figure5:Normalized VGS(th) v.s TJ

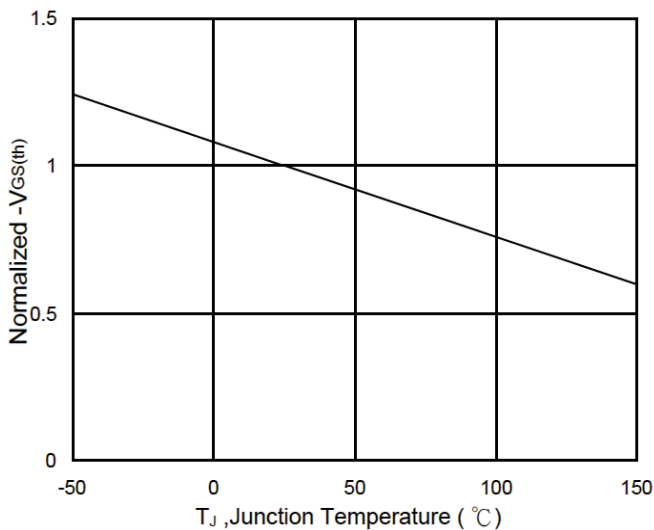
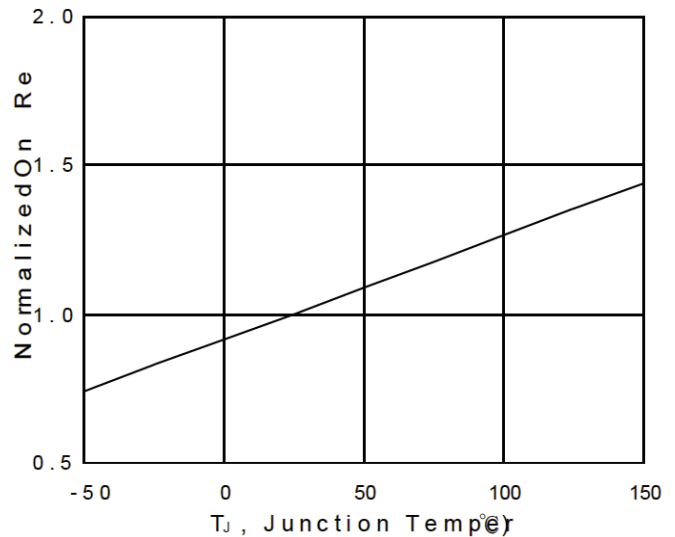


Figure 6:Normalized RDS(on) v.s TJ





P-Channel Typical Performance Characteristics

Figure 7: Capacitance

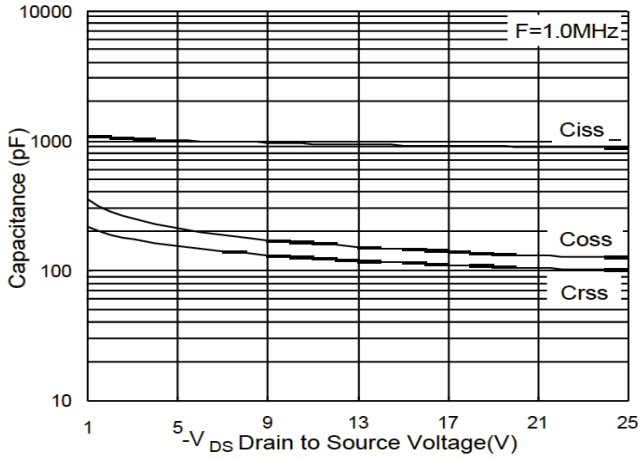


Figure 8: Safe Operating Areare

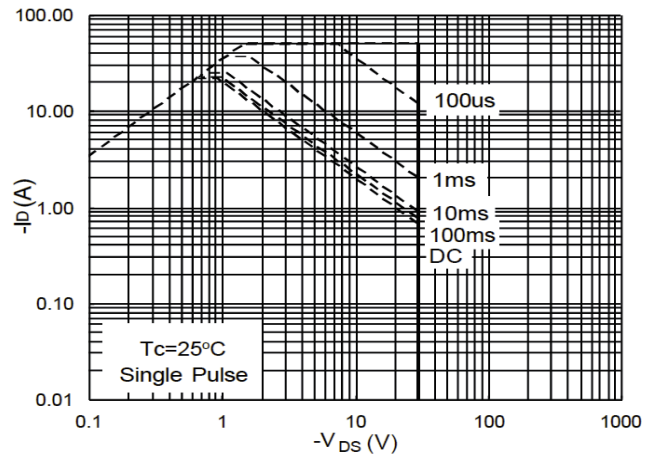


Figure 9: Normalized Maximum Transient

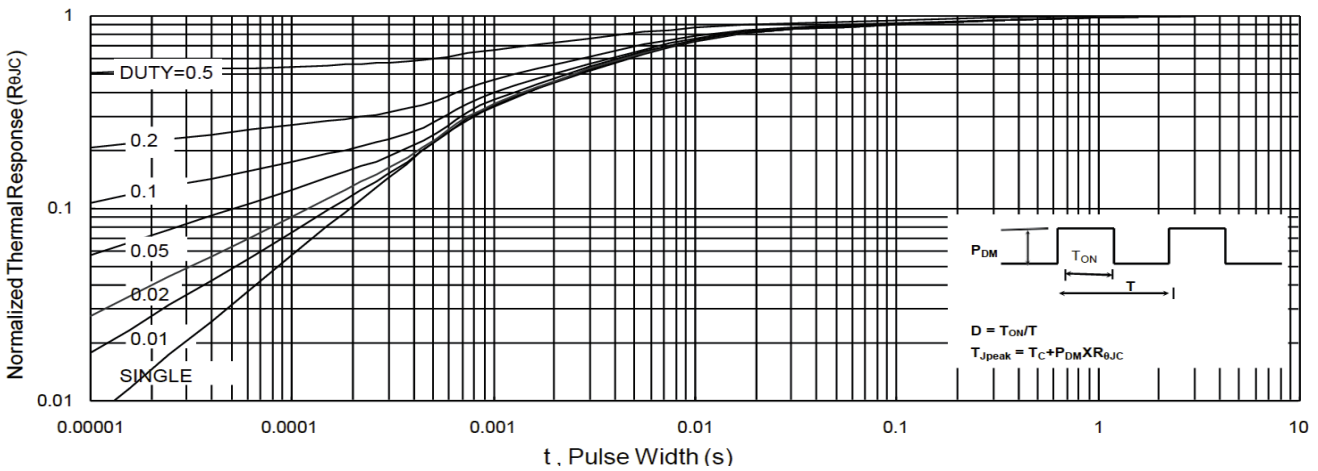


Figure 10: Switching Time Waveformse

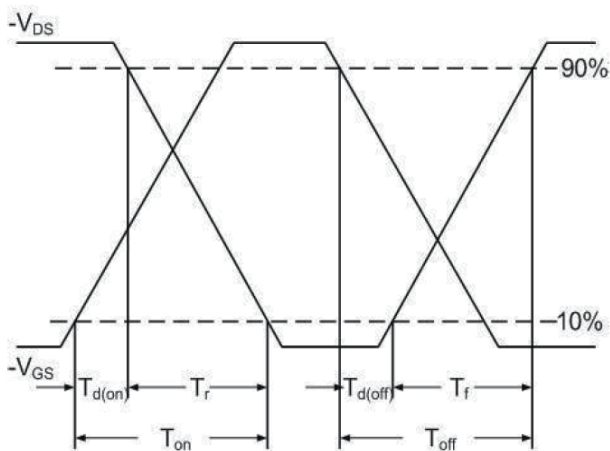
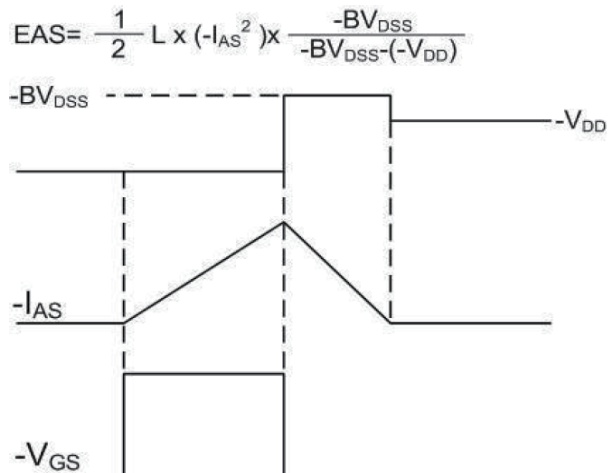
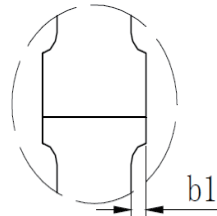
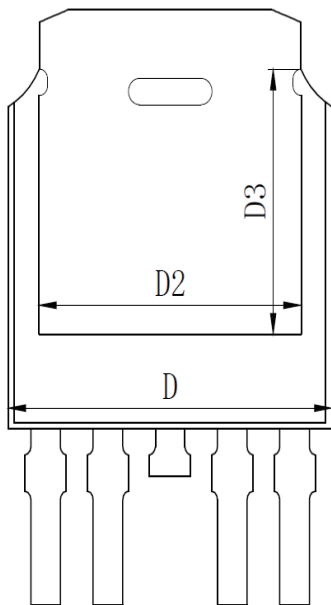
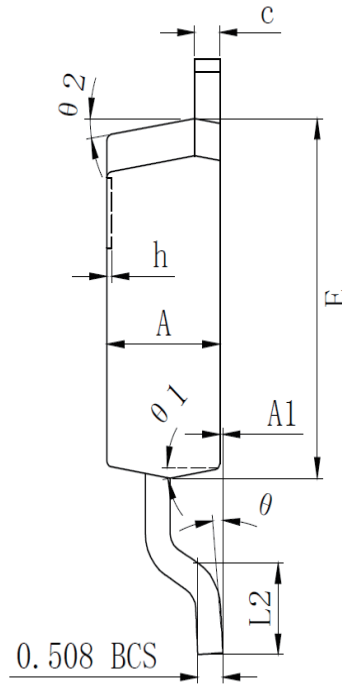
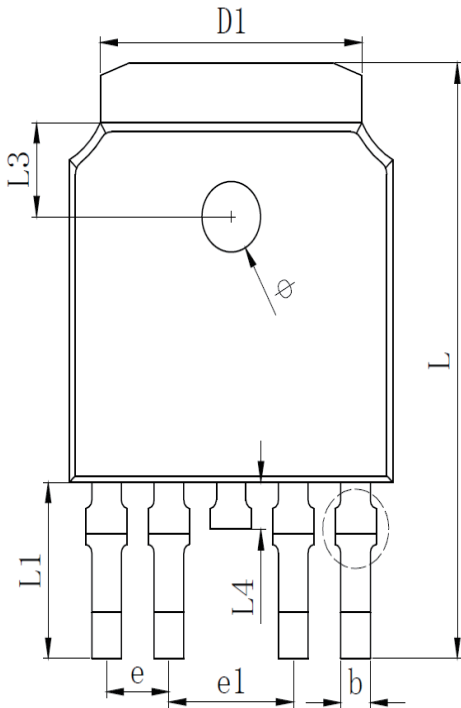


Figure 11: Unclamped Inductive Switching



Mechanical Dimensions for TO-252-4L



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	2.200	2.300	2.400
A1	0.000		0.127
b	0.550	0.600	0.650
b1	0.000		0.120
c(电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334 REF		
D2	5.346 REF		
D3	4.490 REF		
E	6.000	6.100	6.200
e	1.270 TYP		
e1	2.540 TYP		
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.988 REF		
L2	1.400	1.550	1.700
L3	1.600 REF		
L4	0.700	0.800	0.900
Φ	1.100	1.200	1.300
θ	0°		8°
$\theta 1$	9° TYP		
$\theta 2$	9° TYP		